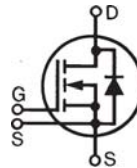


PolarHV™ HiPerFET IXFN 80N50P

Power MOSFET

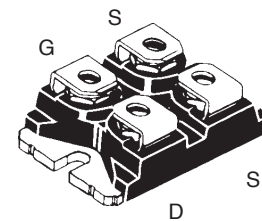
N-Channel Enhancement Mode
Avalanche Rated
Fast Intrinsic Diode

$$\begin{aligned} V_{DSS} &= 500 \text{ V} \\ I_{D25} &= 65 \text{ A} \\ R_{DS(on)} &\leq 65 \text{ m}\Omega \\ t_{rr} &\leq 200 \text{ ns} \end{aligned}$$



| Symbol | Test Conditions | Maximum Ratings | |
|---------------|---|-----------------|------------------|
| V_{DSS} | $T_J = 25^\circ\text{C}$ to 150°C | 500 | V |
| V_{DGR} | $T_J = 25^\circ\text{C}$ to 150°C ; $R_{GS} = 1 \text{ M}\Omega$ | 500 | V |
| V_{GS} | Transient | ± 40 | V |
| V_{GSM} | Continuous | ± 30 | V |
| I_{D25} | $T_C = 25^\circ\text{C}$ | 80 | A |
| I_{DM} | $T_C = 25^\circ\text{C}$, pulse width limited by T_{JM} | 200 | A |
| I_{AR} | $T_C = 25^\circ\text{C}$ | 80 | A |
| E_{AR} | $T_C = 25^\circ\text{C}$ | 80 | mJ |
| E_{AS} | $T_C = 25^\circ\text{C}$ | 3.0 | J |
| dv/dt | $I_S \leq I_{DM}$, $di/dt \leq 100 \text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ\text{C}$, $R_G = 2 \Omega$ | 10 | V/ns |
| P_D | $T_C = 25^\circ\text{C}$ | 700 | W |
| T_J | | -55 ... +150 | $^\circ\text{C}$ |
| T_{JM} | | 150 | $^\circ\text{C}$ |
| T_{stg} | | -55 ... +150 | $^\circ\text{C}$ |
| T_L | 1.6 mm (0.062 in.) from case for 10 s | 300 | $^\circ\text{C}$ |
| V_{ISOL} | 50/60 Hz; $I_{ISOL} \leq 1 \text{ mA}$ | 2500 | V~ |
| M_d | Mounting torque | 1.5/13 | Nm/ib.in. |
| | Terminal connection torque (M4) | 1.5/13 | Nm/ib.in. |
| Weight | | 30 | g |

miniBLOC, SOT-227 B (IXFN)
E153432



G = Gate D = Drain
S = Source

Either source tab S can be used for source current or Kelvin gate return.

Features

- Fast intrinsic diode
- International standard package
- Unclamped Inductive Switching (UIS) rated
- UL recognized.
- Isolated mounting base

Advantages

- Easy to mount
- Space savings
- High power density

| Symbol | Test Conditions ($T_J = 25^\circ\text{C}$ unless otherwise specified) | Characteristic Values | | |
|--------------|---|-----------------------|------|---|
| | | Min. | Typ. | Max. |
| V_{DSS} | $V_{GS} = 0 \text{ V}$, $I_D = 500 \mu\text{A}$ | 500 | | V |
| $V_{GS(th)}$ | $V_{DS} = V_{GS}$, $I_D = 8 \text{ mA}$ | 3.0 | | 5.0 V |
| I_{GSS} | $V_{GS} = \pm 30 \text{ V}_{DC}$, $V_{DS} = 0$ | | | $\pm 200 \text{ nA}$ |
| I_{DSS} | $V_{DS} = V_{DSS}$ $V_{GS} = 0 \text{ V}$ | | | 25 μA 1 mA $T_J = 125^\circ\text{C}$ |
| $R_{DS(on)}$ | $V_{GS} = 10 \text{ V}$, $I_D = 0.5 I_{D25}$, Note 1 | | | 65 m Ω |

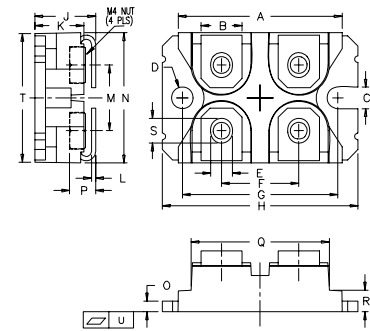
DS99477(09/05)

| Symbol | Test Conditions | Characteristic Values ($T_J = 25^\circ\text{C}$ unless otherwise specified) | | |
|--------------|---|---|------|----------|
| | | Min. | Typ. | Max. |
| g_{fs} | $V_{DS} = 20\text{ V}; I_D = 0.5 I_{D25}$, Note 1 | 35 | 70 | S |
| C_{iss} | | | 12.7 | nF |
| C_{oss} | $V_{GS} = 0\text{ V}, V_{DS} = 25\text{ V}, f = 1\text{ MHz}$ | | 1280 | pF |
| C_{rss} | | | 120 | pF |
| $t_{d(on)}$ | | | 25 | ns |
| t_r | $V_{GS} = 10\text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25}$ | | 27 | ns |
| $t_{d(off)}$ | $R_G = 2\ \Omega$ (External) | | 70 | ns |
| t_f | | | 18 | ns |
| $Q_{g(on)}$ | | | 195 | nC |
| Q_{gs} | $V_{GS} = 10\text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25}$ | | 70 | nC |
| Q_{gd} | | | 64 | nC |
| R_{thJC} | | | | 0.18 K/W |
| R_{thCK} | | 0.05 | | K/W |

Source-Drain Diode

| Symbol | Test Conditions | Characteristic Values ($T_J = 25^\circ\text{C}$ unless otherwise specified) | | |
|-----------|--|---|------|---------------|
| | | Min. | Typ. | Max. |
| I_s | $V_{GS} = 0\text{ V}$ | | | 80 A |
| I_{SM} | Repetitive | | | 200 A |
| V_{SD} | $I_F = I_S, V_{GS} = 0\text{ V}$, Note 1 | | | 1.5 V |
| t_{rr} | $I_F = 25\text{ A}, -di/dt = 100\text{ A}/\mu\text{s}$ | | | 200 ns |
| Q_{RM} | $V_R = 100\text{ V}, V_{GS} = 0\text{ V}$ | | 0.8 | μC |
| fl_{RM} | | | 8 | A |

Note 1: Pulse test, $t \leq 300\ \mu\text{s}$, duty cycle $d \leq 2\%$

SOT-227B miniBLOC (IXFN)


| SYM | INCHES | | MILLIMETERS | |
|-----|--------|-------|-------------|-------|
| | MIN | MAX | MIN | MAX |
| A | 1.240 | 1.255 | 31.50 | 31.88 |
| B | .307 | .323 | 7.80 | 8.20 |
| C | .161 | .169 | 4.09 | 4.29 |
| D | .161 | .169 | 4.09 | 4.29 |
| E | .161 | .169 | 4.09 | 4.29 |
| F | .587 | .595 | 14.91 | 15.11 |
| G | 1.186 | 1.193 | 30.12 | 30.30 |
| H | 1.496 | 1.505 | 38.00 | 38.23 |
| J | .460 | .481 | 11.68 | 12.22 |
| K | .351 | .378 | 8.92 | 9.60 |
| L | .030 | .033 | 0.76 | 0.84 |
| M | .496 | .506 | 12.60 | 12.85 |
| N | .990 | 1.001 | 25.15 | 25.42 |
| O | .078 | .084 | 1.98 | 2.13 |
| P | .195 | .235 | 4.95 | 5.97 |
| Q | 1.045 | 1.059 | 26.54 | 26.90 |
| R | .155 | .174 | 3.94 | 4.42 |
| S | .186 | .191 | 4.72 | 4.85 |
| T | .968 | .987 | 24.59 | 25.07 |
| U | -.002 | .004 | -0.05 | 0.1 |

IXYS reserves the right to change limits, test conditions, and dimensions.

Fig. 1. Output Characteristics
@ 25°C

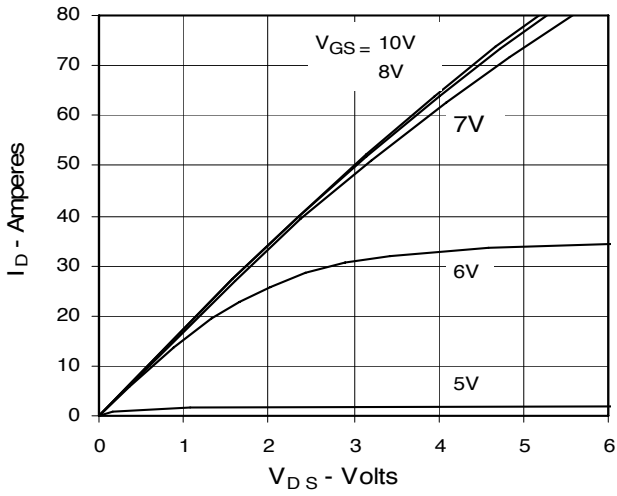


Fig. 2. Extended Output Characteristics
@ 25°C

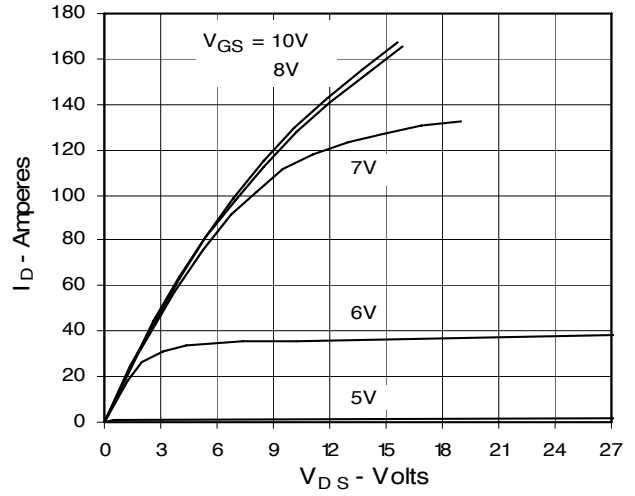


Fig. 3. Output Characteristics
@ 125°C

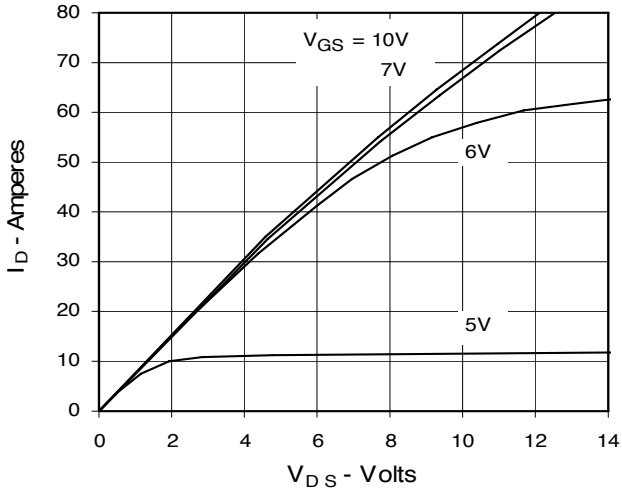


Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 40A$ vs. Junction Temperature

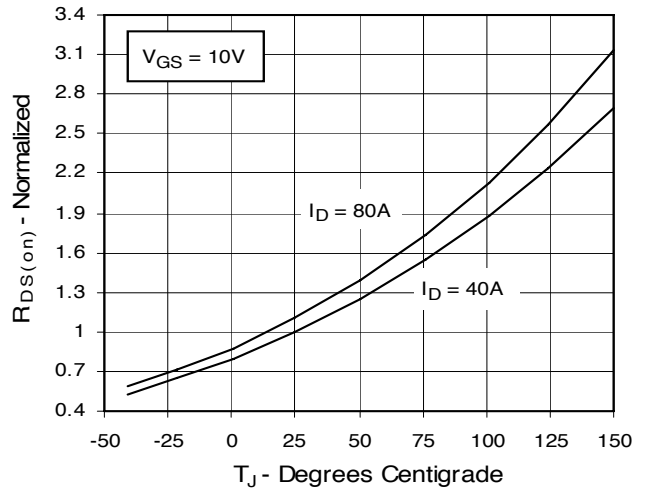


Fig. 5. $R_{DS(on)}$ Normalized to $I_D = 40A$ vs. I_D

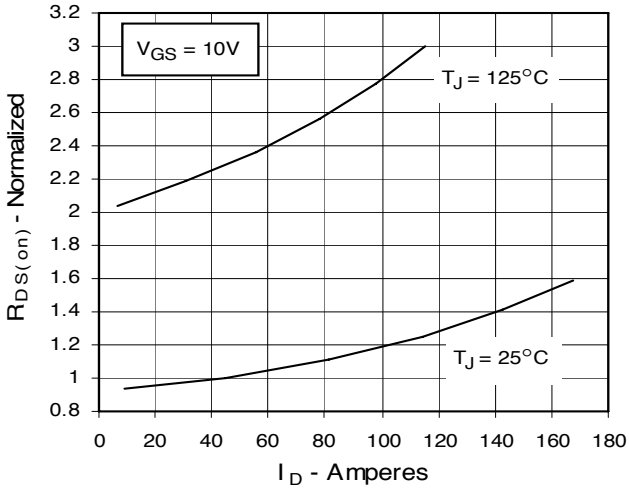


Fig. 6. Drain Current vs. Case Temperature

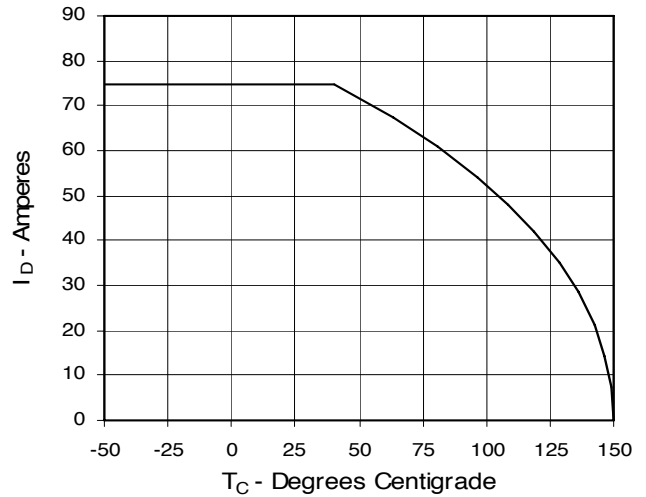


Fig. 7. Input Admittance

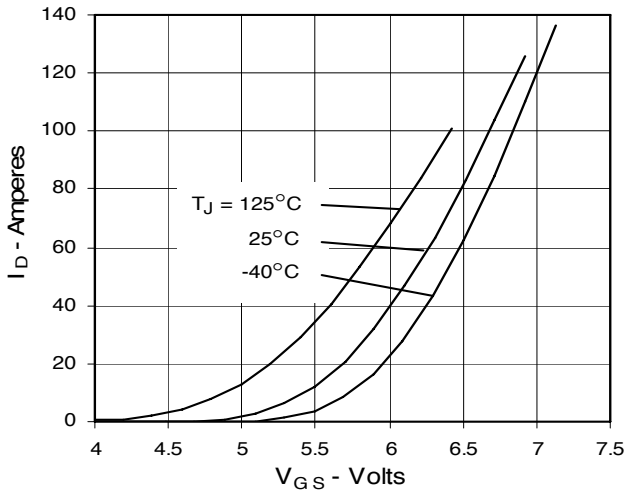


Fig. 8. Transconductance DataSheet4U.com

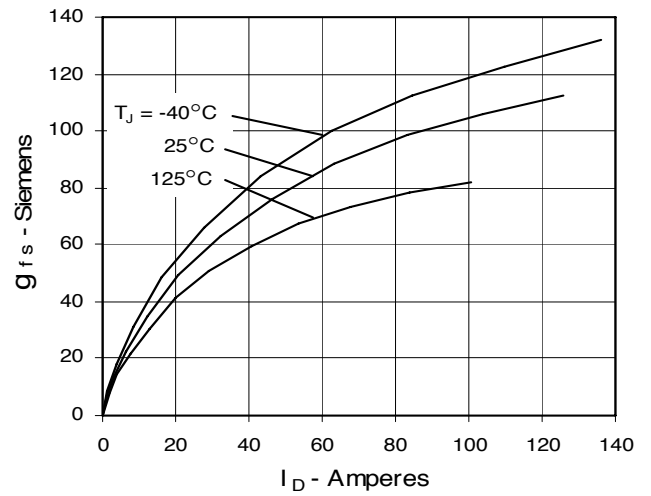


Fig. 9. Source Current vs. Source-To-Drain Voltage

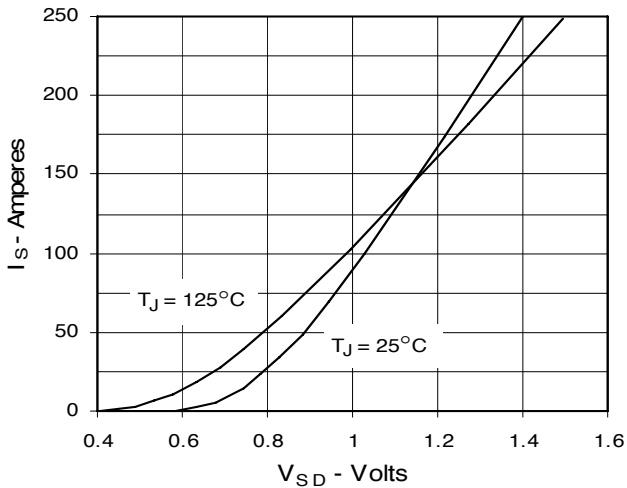


Fig. 10. Gate Charge

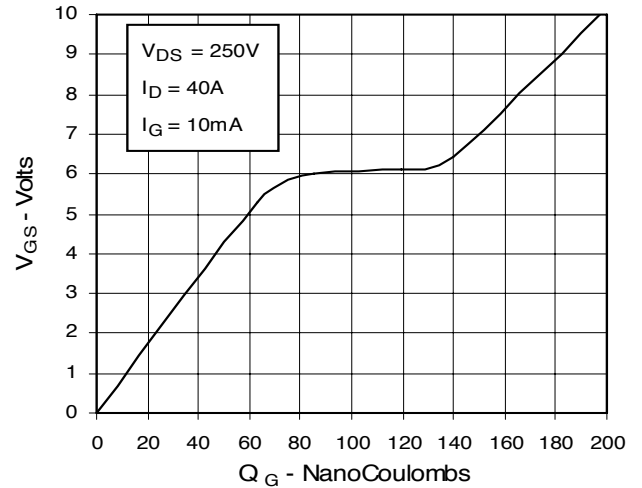


Fig. 11. Capacitance

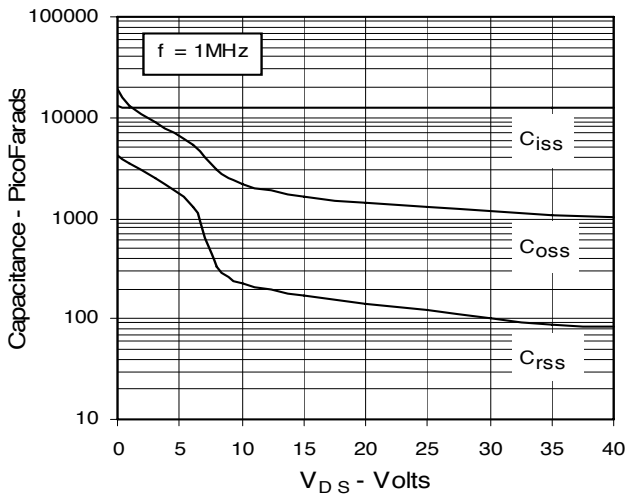


Fig. 12. Forward-Bias Safe Operating Area

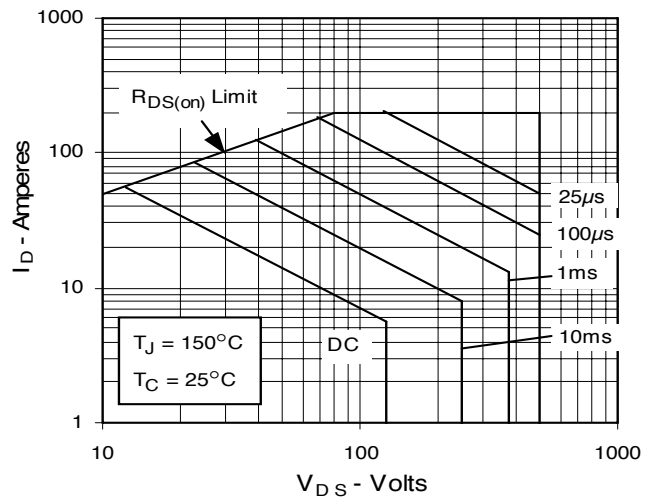


Fig. 13. Maximum Transient Thermal Resistance

